

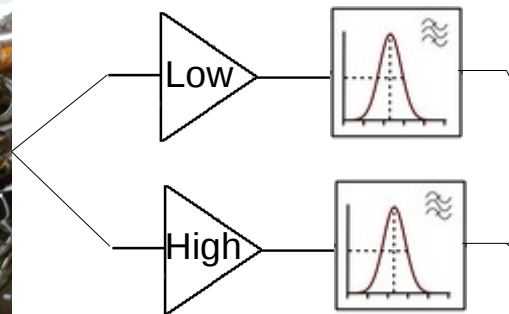
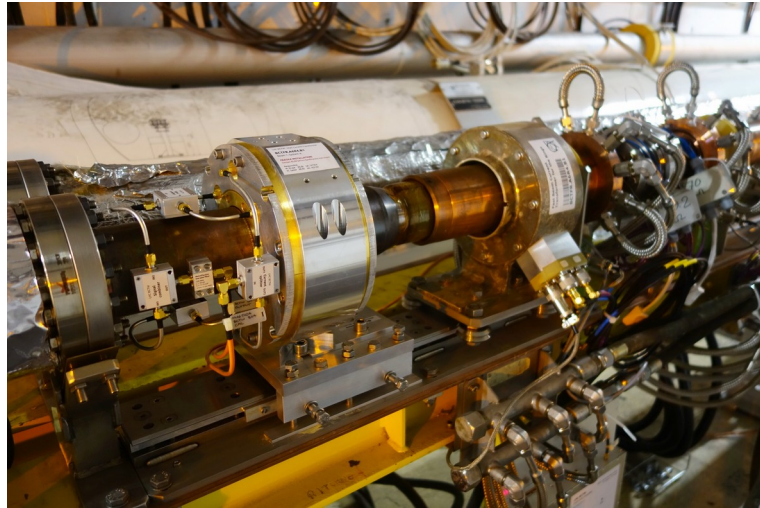
A New Acquisition System For The SPS And LHC Fast BCTs

Jiri Kral

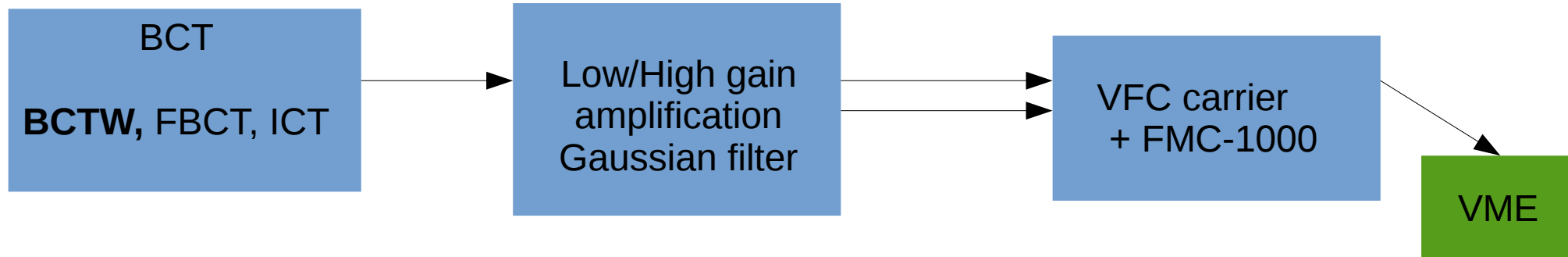
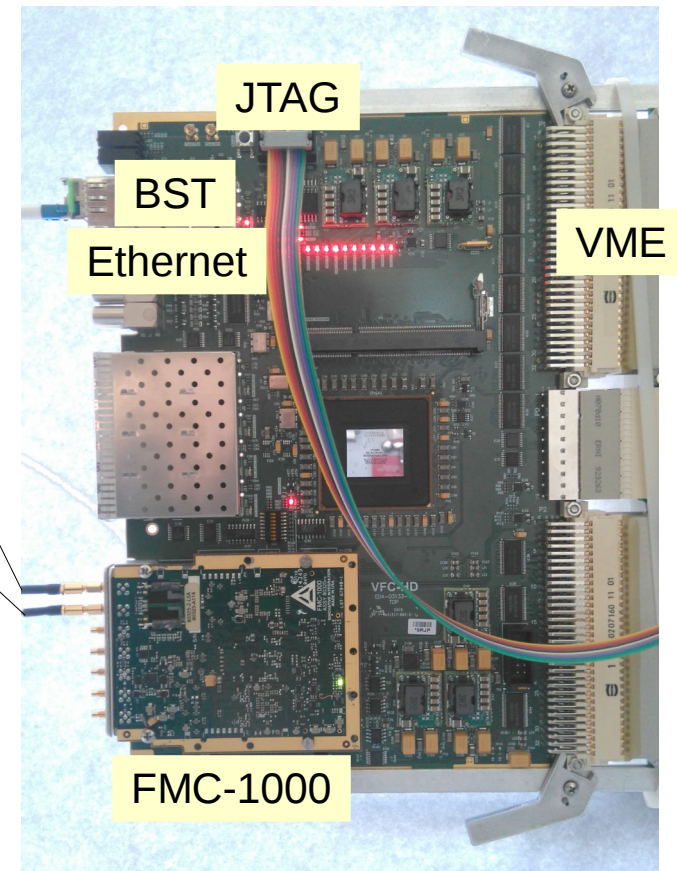
Overview

- New LHC and SPS per bunch intensity measurement system
 - Below 1% precision
 - Up to high (2×10^{10} charges) and low gain (2×10^{11} charges) channels
- Based on the VFC board (CERN) with FMC-1000, 1 GHz 2-channel ADC mezzanine (supplier)
- 650 MHz ADC sampling rate currently (1 GHz under investigation)

Hardware

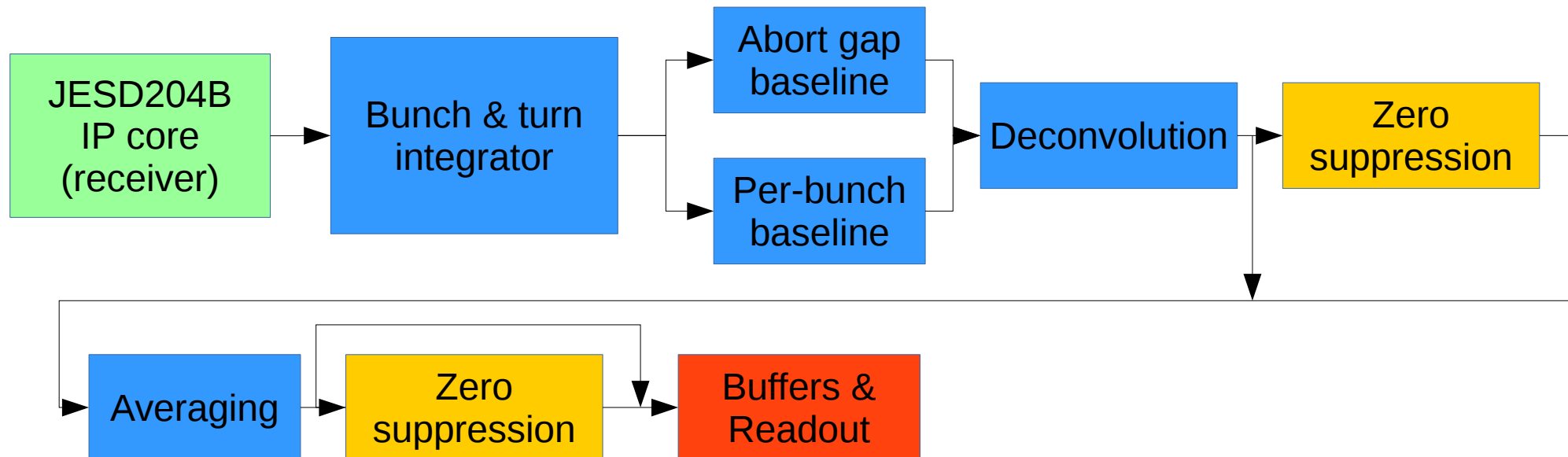


150 MHz bandwidth



Data processing in the firmware

- JESD204B line in between ADC and FPGA, 4 x 6.5 Gbit/s
- Integration, baseline subtraction on per-bunch bases
- Deconvolution to remedy tails crossing to the next bunch
- Averaging over N turns (224, ...)
- Possibility of zero suppression of the raw or averaged data



Available measurements

- Continuous
 - Per **bunch intensity** integrals, averaged over N turns
 - **Turn intensity** integral, averaged over N turns
 - Beam filling pattern

- Snapshots

- Raw ADC data
- Unaveraged bunch integrals
- Computed baselines
- Unaveraged turn integral

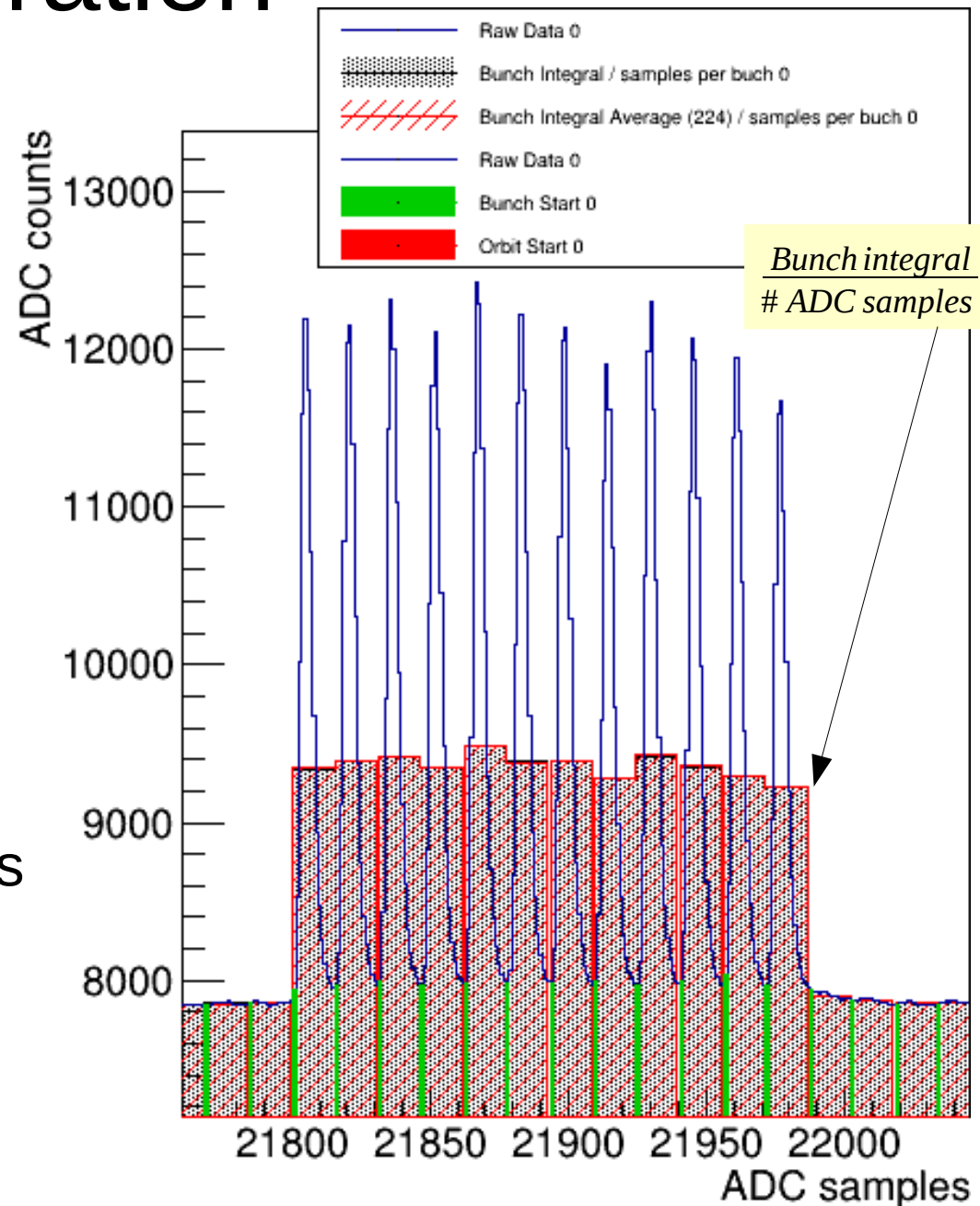
$$\langle I_{bunch,i} \rangle = \frac{\sum_{n=0}^{N_{turnavg}-1} I_{bunch,i,n}}{N_{turnavg}}$$

$$\langle I_{turn} \rangle = \frac{\sum_{n=0}^{N_{turnavg}-1} I_{turn,n}}{N_{turnavg}}$$

- All measurements are time stamped using the BST time

Integration

- Integrating constant # of samples per bunch
- **Free running** 650 MHz ADC sampling clock
 - LHC frequency out of FMC-1000 VCXO range
 - 16 samples / bunch
- Averaging over many turns
 - i.e.: many sampling phases
 - Immune to small phase shifts

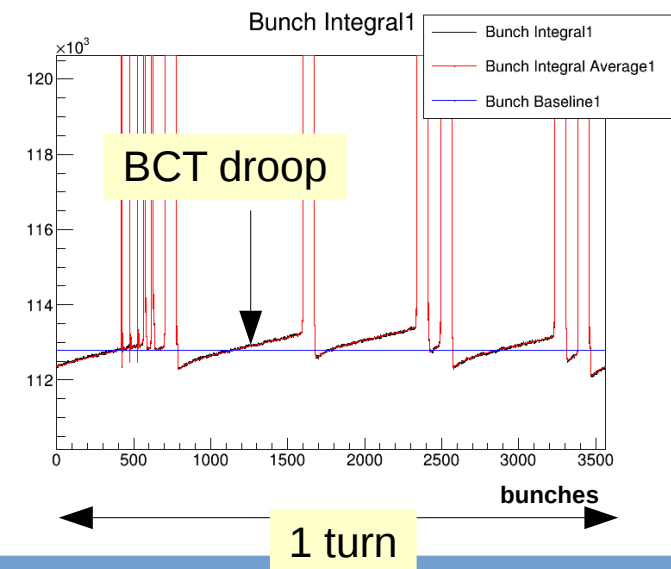
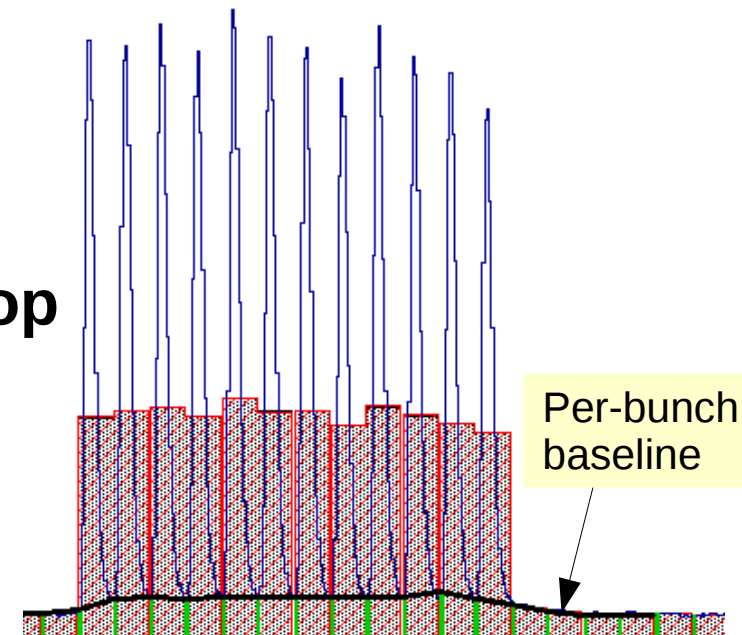


Baseline subtraction

- Per bunch baseline reconstruction
 - Signal overflow to following bunches
 - Per turn not possible due to **BCT droop**
- Linear interpolation in between two points
 - Either with fixed phase
 - Or min of 2 consecutive samples

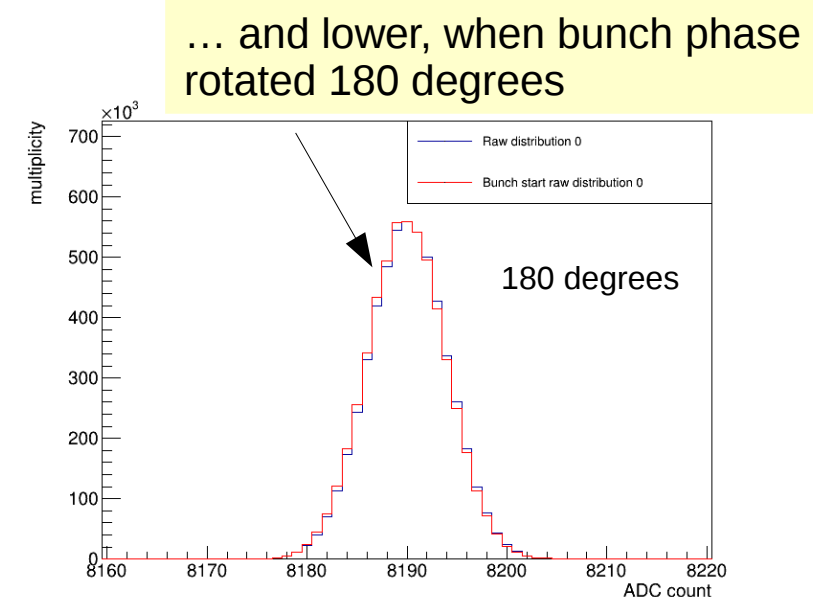
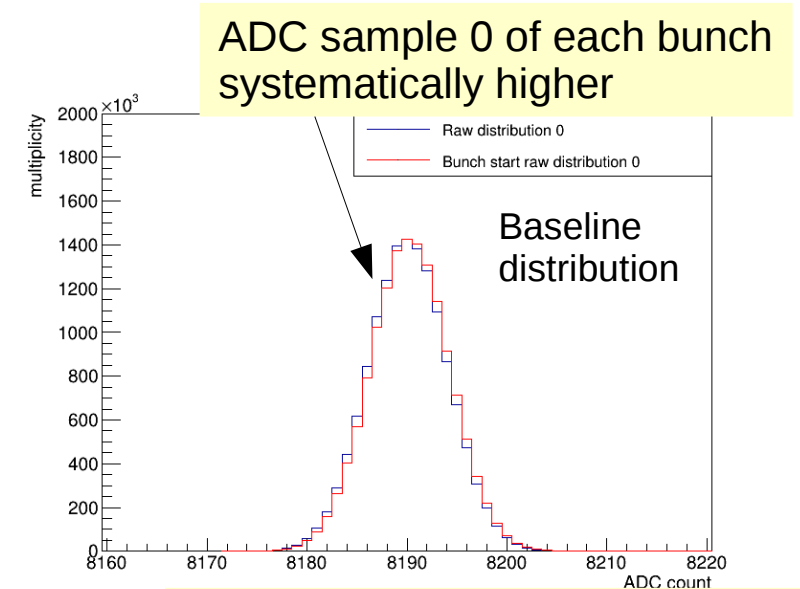
$$baseline_{bunch} = \frac{\sum_{i=0}^1 \min_{bunch+i}(sample_0, sample_1)}{2}$$

- Zero suppression with a constant threshold

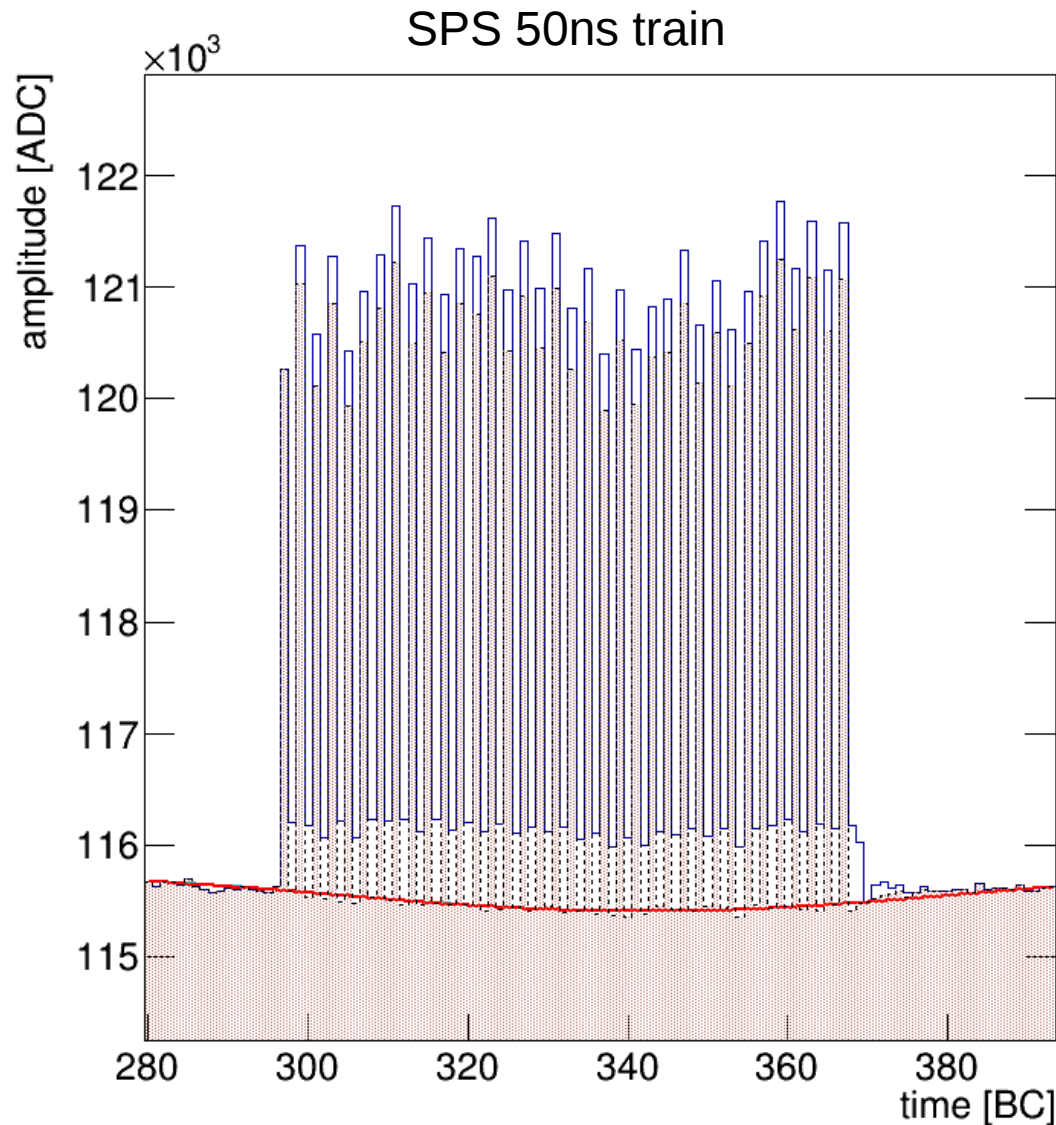


Baseline corrections

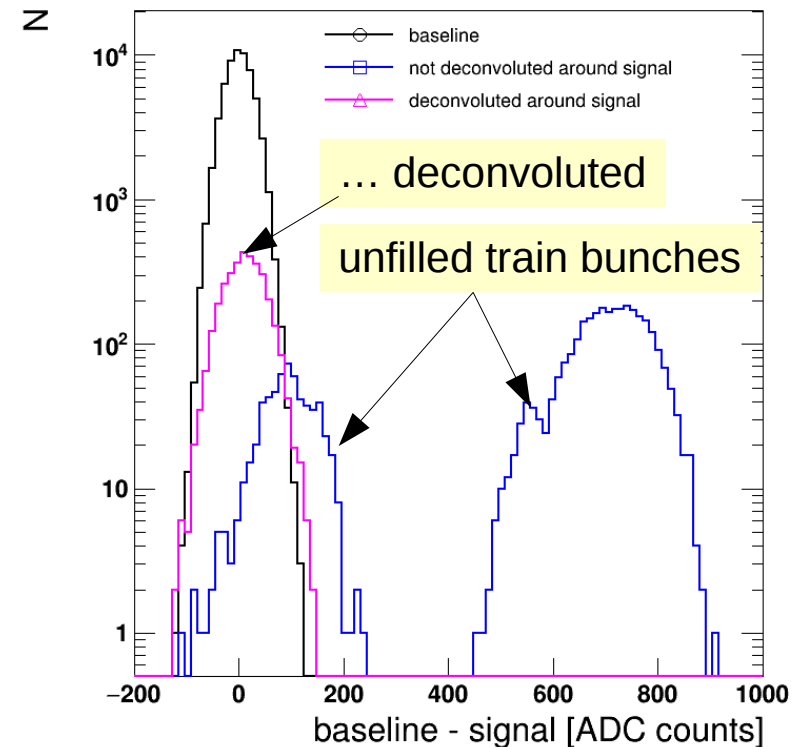
- Beam synchronous noise, FPGA switching noise or the baseline *min()* of 2 samples requirement create a **constant offset**
 - Constant per bunch offset correction
- **Rounding error** on turn integral
 - Constant offset turn correction
 - Magnitude close to pilot bunch intensity in low gain channel



Deconvolution

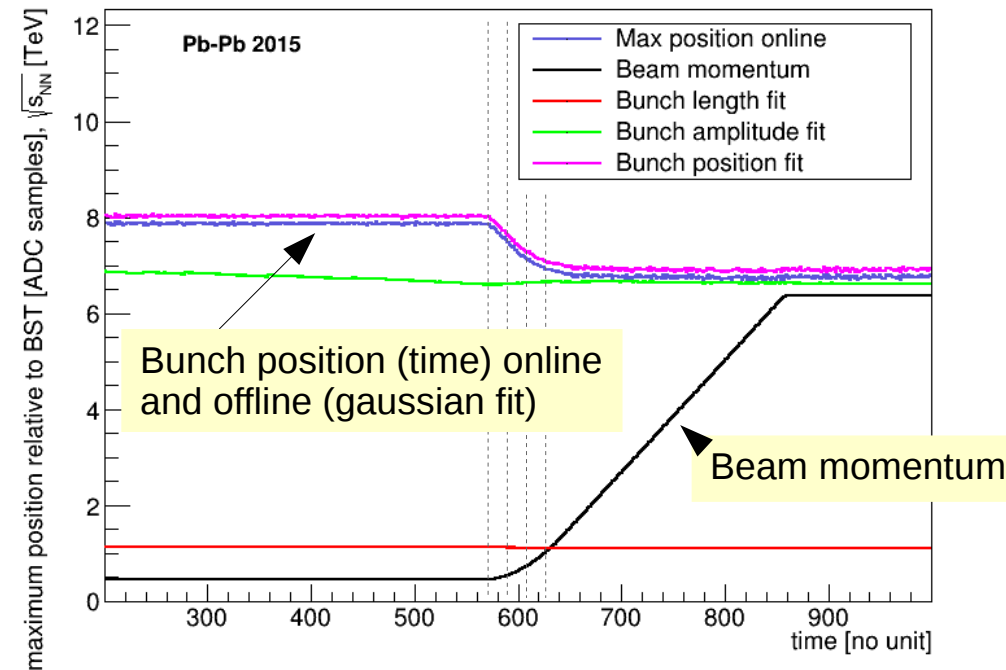
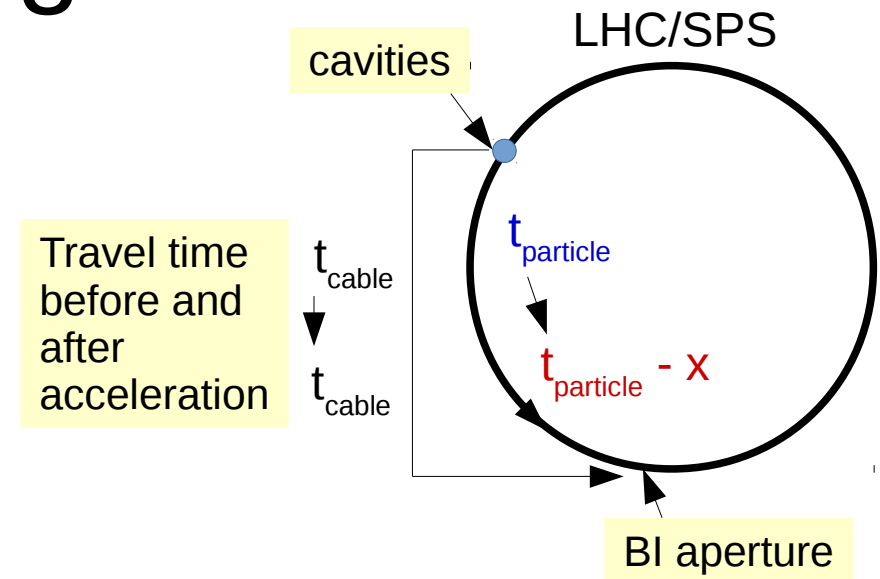


- Simple deconvolution of 10 consecutive bunches seems to give reasonable results



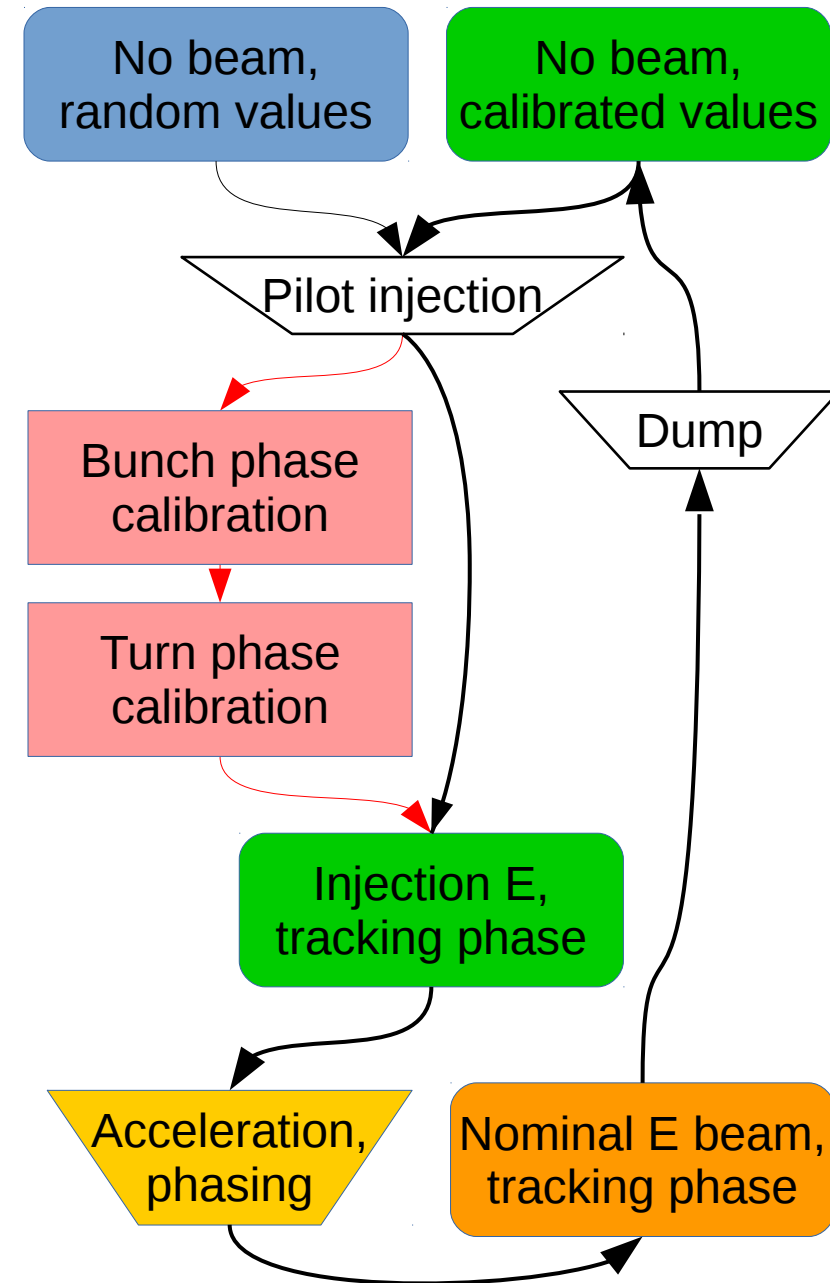
Timing

- After acceleration, the **beam arrives sooner** to the measurement point than clock edge does
 - Change in sampling phase
- Shift of up to -12 ns in SPS
- In LHC, -1.5 ns observed for heavy ions



Timing correction

- **On-line peak finding** to identify maximum of each bunch signal
 - Bunch boundaries relative to the maximum position
- BST clock phase shifted and **tuned continuously** to the present beam
 - Supplies bunch boundaries of unfilled bunches
- In case of “adiabatic” change, possibility to track bunches across bunch boundaries ($>25\text{ns}$)
- **Auto-calibration** possible on pilot
 - Of both **bunch and turn phase**

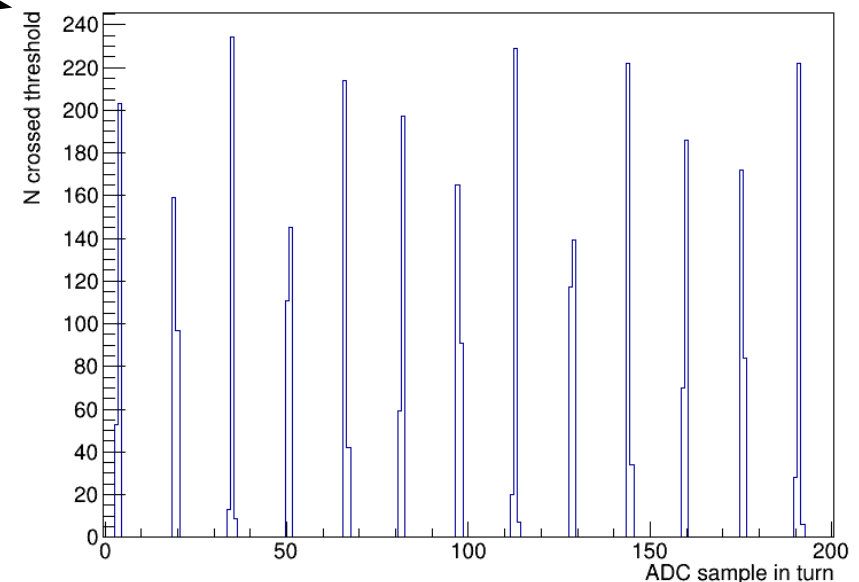
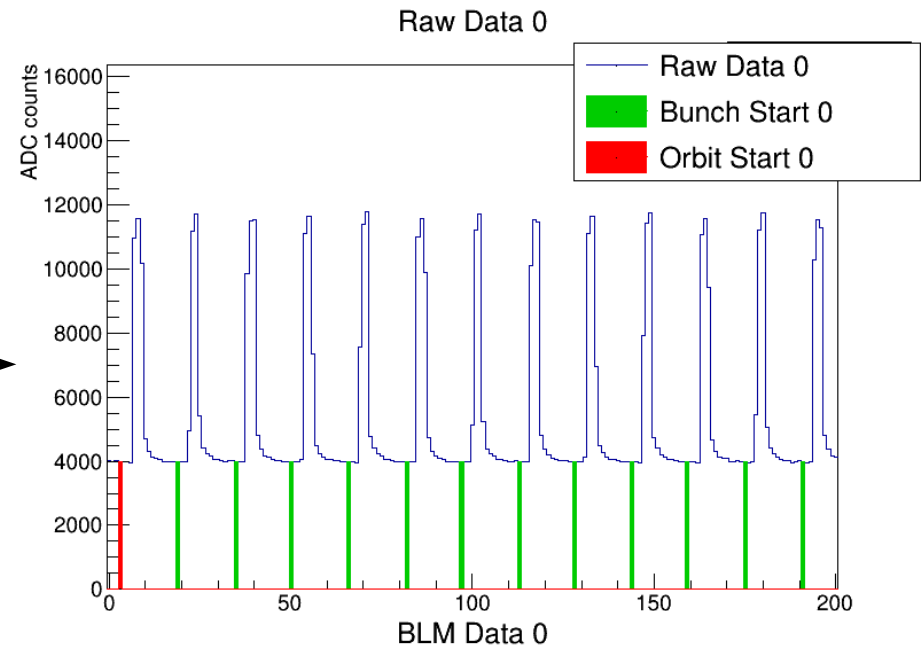


Automation

- **Boot ROM** includes configuration of the VFC board (voltages), FMC-1000 clock generation, ADC and JESD204B link
 - No need for complicated software driven boot
 - Simple ROM updates without need to recompile the FW
- Several **automated calibration** procedures available
 - Bunch baseline correction
 - Turn baseline correction
 - Beam timing
- On-board beam **dump detection** to trigger snapshot
 - Dump trigger might arrive quite late

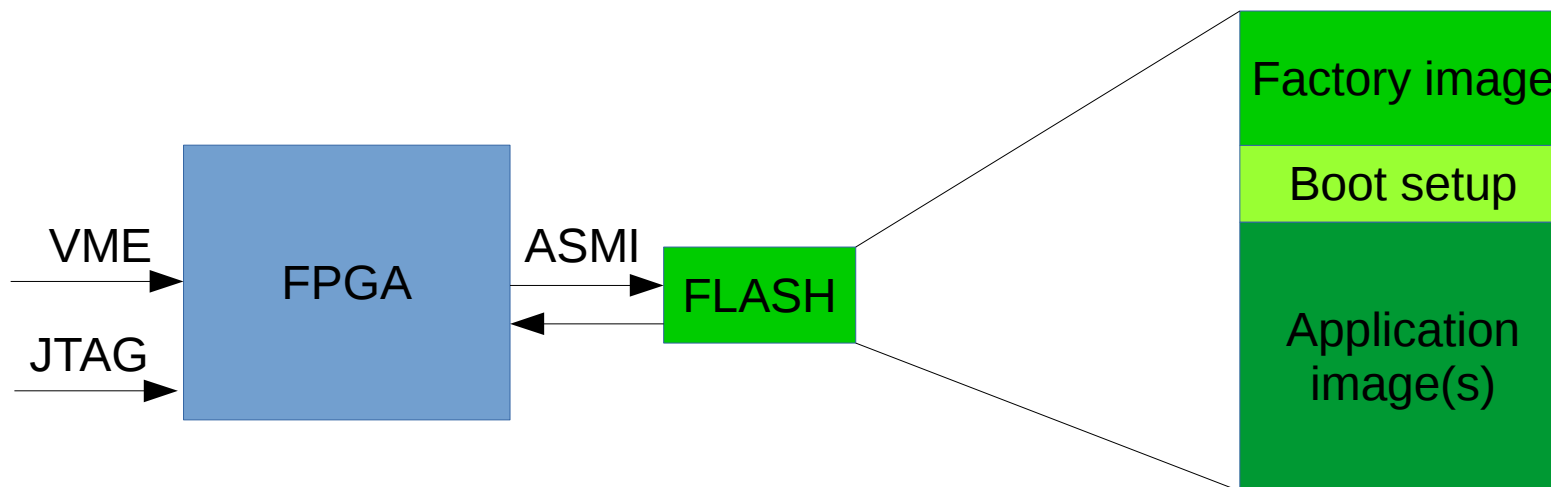
Beam Loss Monitor

- Diamond Beam Loss Monitor FW module was developed
- Shares raw ADC snapshot data →
- Implements new histogram of, $N = \#$ of ADC samples in turn, values →
 - Incremented on first sample that crosses threshold
 - Relative to either BST turn start or external trigger



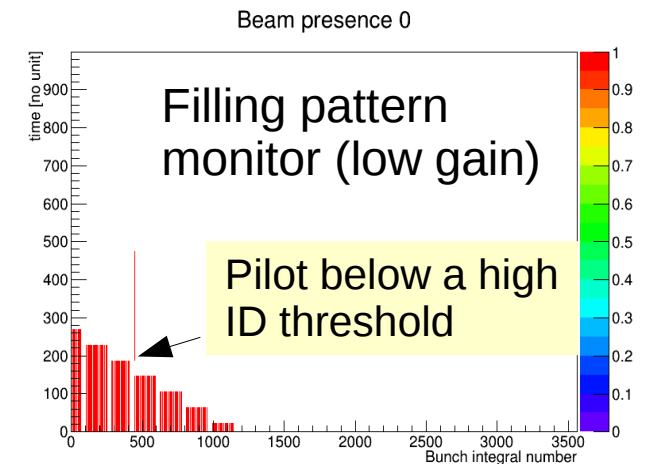
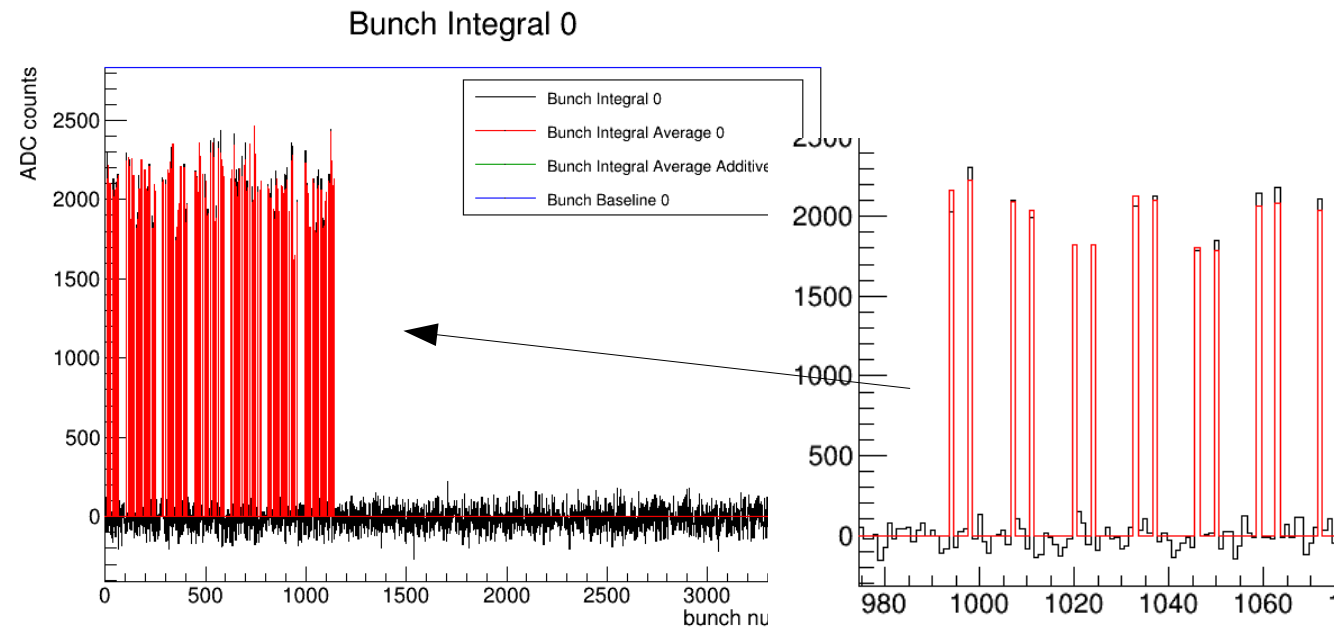
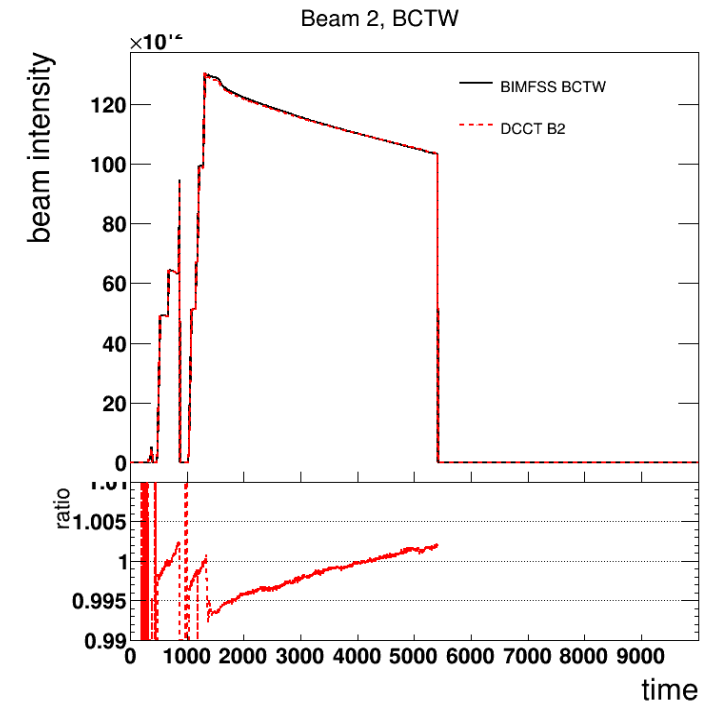
Deployment

- VFC card includes **flash memory** which can hold the FW
- VFC **factory (golden) image** prepared
 - Accesses flash via VME or JTAG, loads application image
 - Write protected **avoids bricking** the board with a failed flash
 - **Watchdog** reconfigures to factory, if application image fails
- Available to **all VFC card users** (with documentation :)



First intensity measurement

- Relative agreement with DCCT **within 1%** for pp
 - Observed **debunching**
 - No absolute calibration, ADC linearity correction, etc.

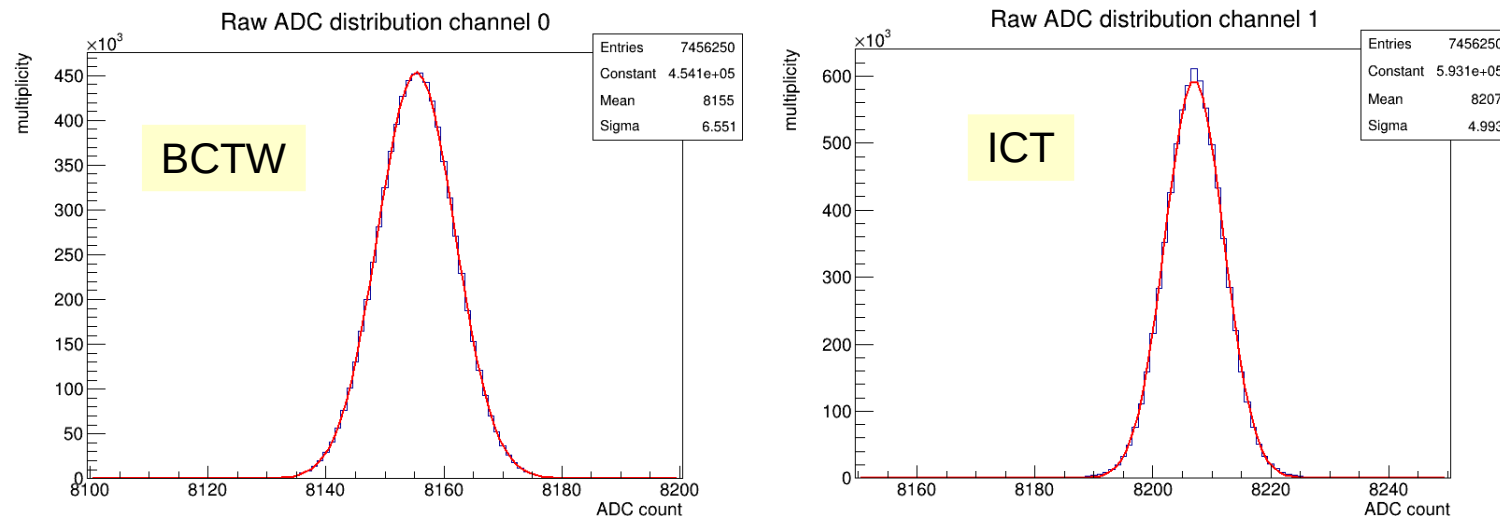


ICT BCTW noise measurement

- Evaluated BCTW and ICT noise background
 - Different gain and bandwidth (60 MHz ICT, 150 MHz BCTW)
 - Gain aligned using comparison to the DCCT data ($f = 1.23$)
 - Bandwidth factor from aligning white noise powers ($f = 1.58$)

$$N_{power}[dBm] = 20 \log(\sigma[V]) - 10 \log(R) + 30; R = 50 \text{ Ohm}$$

Presumed white noise → proportional power to bandwidth



- $\Sigma_{BCTW} = 6.55 * 1.23 / 1.58 = 5.10 \rightarrow \sigma_{BCTW} / \sigma_{ICT} = 1.02$
- Noise ratio on bunch integrals: $\sigma_{BCTW} / \sigma_{ICT} = 1.08$

1 GHz sampling

- Under investigation
- Several caveats
 - Standard VFC cards FPGA Arria V **GX transceivers** do **not support** necessary JESD204B data rate (> 6.5 GBit/s)
 - Replaced with similar pinout Arria V GT chip
 - The Altera Arria V JESD204B **IP core** does **not support** the necessary data rate (even for GT chip)
 - Transceivers can receive 10 GBit/s data stream
 - Write a simple limited JESD204B receiver
 - 1 out of 4 high speed differential lines is **routed** to transceiver banks which do not support > 6.5 GBit/s
 - Re-wire, PCB revision, FMC connector adapter, ...

Software

- Software under development
- Capable of pulling snapshot data without important impact on continuous measurements readout
- IRQ driven
- Database archival of the main data points that are necessary for the commissioning



Conclusion

- **Firmware** for beam intensity measurement using fast BCTs was **implemented**
 - Foundation for digital processing of BCT data on VFC cards for **not only intensity measurements**
 - “Outreach” to other projects (BLM, factory FW image, ...)
- Hardware was tested and evaluated
- First measurements were performed on 2015 pp and Pb-Pb fills at LHC and SPS
- Absolute calibration system under development
- Getting ready for the 2016 run and final commissioning

Credits

The boss: David Belohrad

Firmware: Jiri Kral

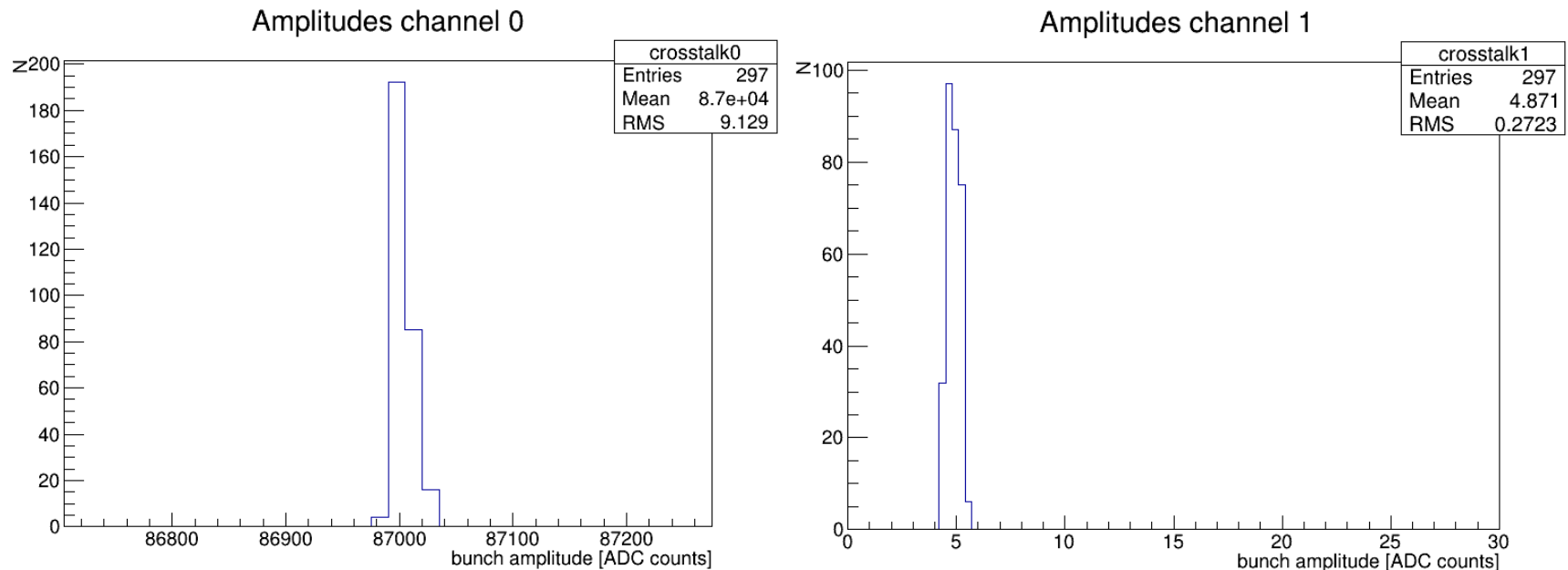
Software: Stephane Bart Pedersen

Special thanks to: Andrea Boccardi, Manoel Barros Marin
for the help with the VFC board
Michal Krupa, Marek Gasior
for the BCTW part

Backup

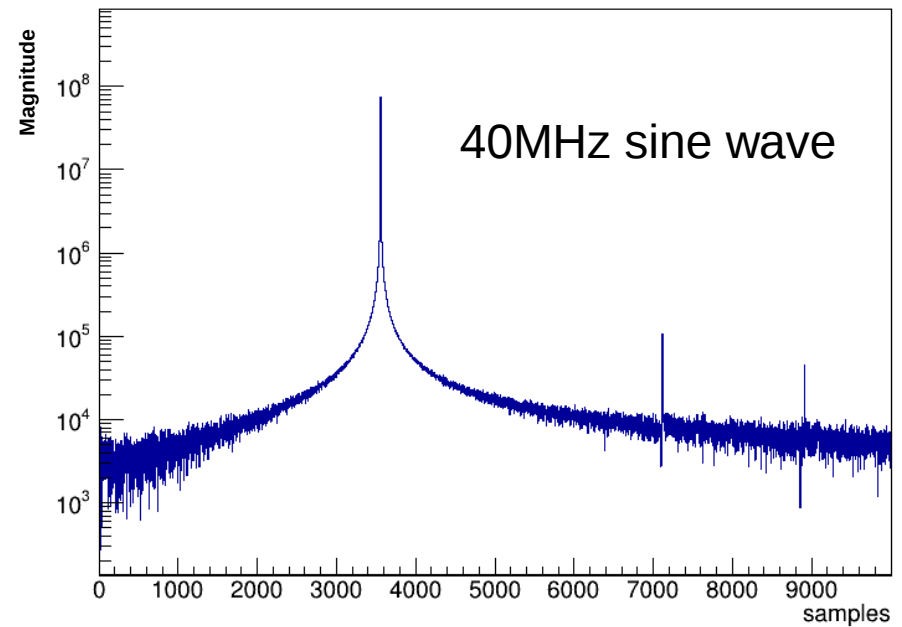
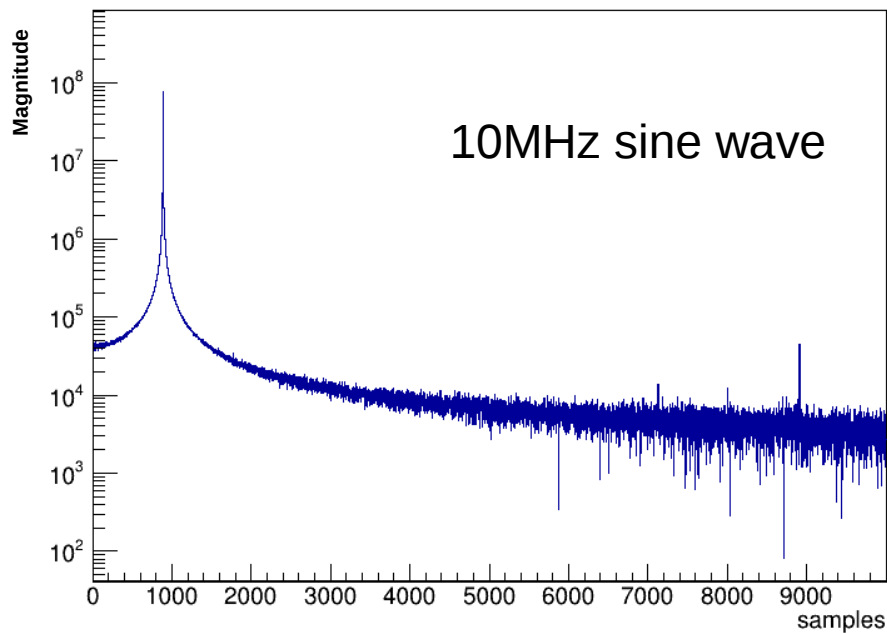
Channel crosstalk

- -80 dB measured (ADC -95 dB according to data sheet)
- Measured in amplitude domain
 - Repetitive pattern of signals simulating bunches injected in one channel, second channel terminated
 - Averaged measurement over ~130k turns
 - Observed induced amplitude



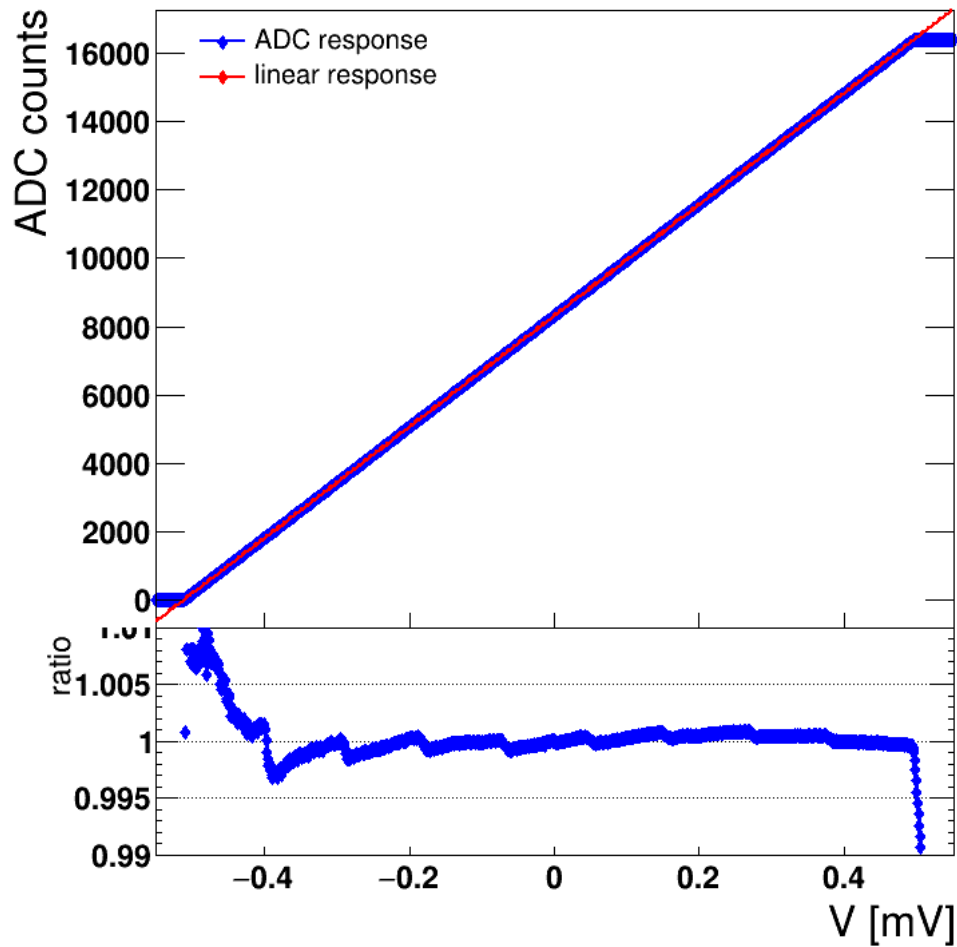
FFT

- FFT of sine wave injected into one channel
- Response clean

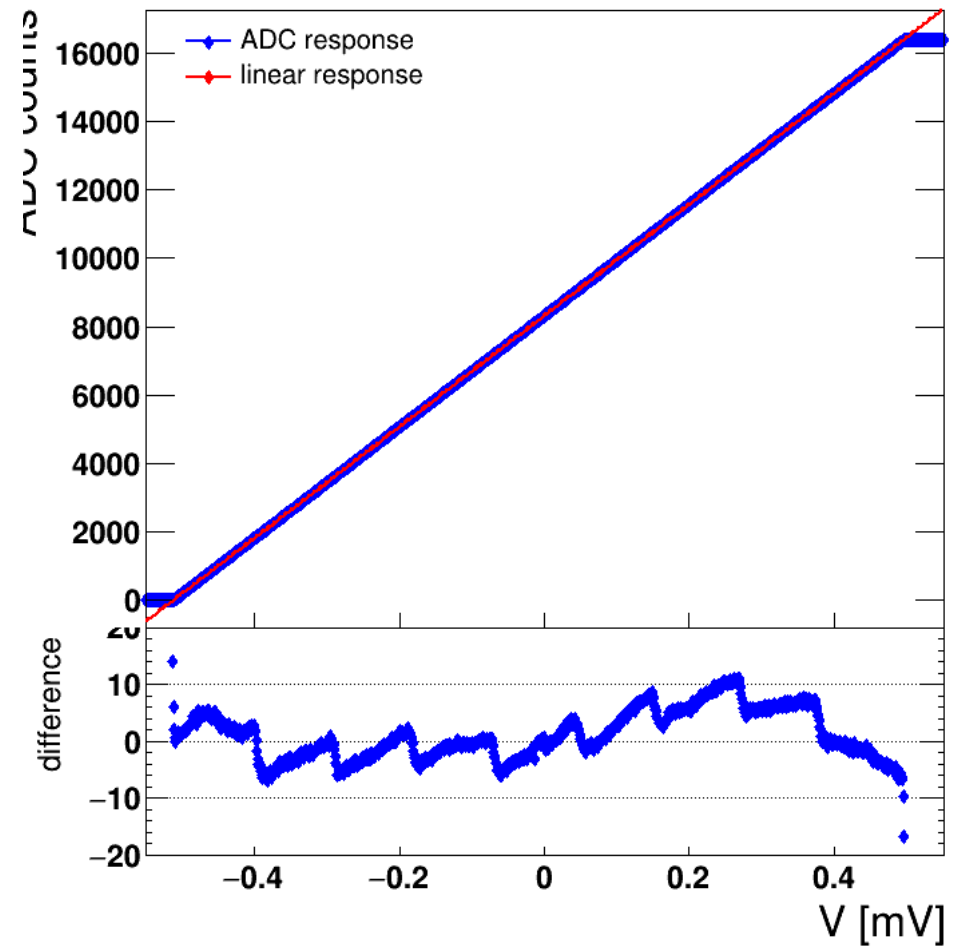


ADC linearity

Channel 0

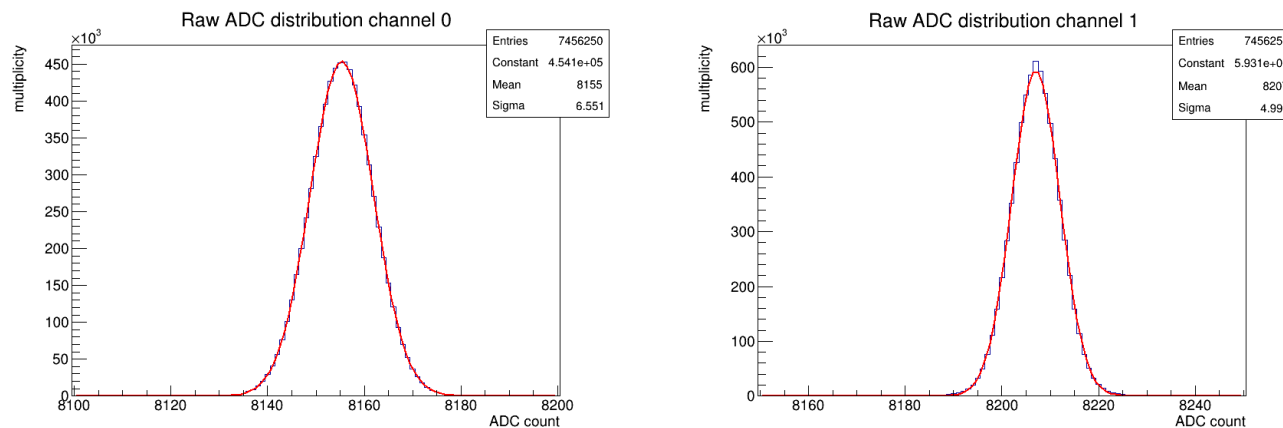


Channel 0



LHC ICT BCTW noise comparison

- ICT installed on B1 (ch1), BCTW on B2 (ch0), 1 RF dist. LG channels used for ICT, FMC card #1, BCTW connected without RF dist.
 - Bandwidth limit for ICT is 60 MHz from RF dist., 150 MHz for BCTW
 - Correction factor 1.58 $N_{power}[dBm] = 20 \log(\sigma[V]) - 10 \log(R) + 30; R = 50 \text{ Ohm}$ Presumed white noise \rightarrow proportional power to bandwidth
- Beam intensity measurement by the new device was correlated with B1/B2 ratio from DCCT TIMBER data to scale the unequal gains
 - Correction gain factor computed: $BCTW * 1.23 / ICT = 1$



- Distribution of raw ADC signal was obtained (without beam)
- Corrected $\sigma_{BCTW} = 6.55 * 1.23 / 1.58 = 5.10 \rightarrow \sigma_{BCTW}/\sigma_{ICT} = 1.02$
- Noise ratio on bunch integrals (same method): $\sigma_{BCTW}/\sigma_{ICT} = 1.08$

